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10.9.02
C. Moore

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Seiichi HAYASHI, et al.
Serial No. : 09/852,111
Filed : May 9, 2001
For : METHOD AND APPARATUS FOR MEASURING
THIN FILM, AND THIN FILM DEPOSITION
SYSTEM
Group Art Unit : 2882
Examiner : David P. Porta

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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to ASSISTANT COMMISSIONER FOR PATENTS, WASHINGTON, DC 20231 on September 27, 2002.

Herbert F. Ruschmann

(Name)

(Signature)

Assistant Commissioner for Patents
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

Submitted herewith is an Information Disclosure Citation together with a copy of reference referred to therein.

Respectfully submitted,

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